

**Search Notes**

Application/Control No.

10/601,275

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

YE ET AL.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	13	12/8/2006	DWY
429	40	12/8/2006	DWY
429	42	12/8/2006	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
429	13	12/8/2006	DWY
429	40	12/8/2006	DWY
429	42	12/8/2006	DWY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	12/8/2006	DWY
Inventorship Search	12/8/2006	DWY